

TOSHIBA Field Effect Transistor Silicon N Channel MOS Type (兀MOS)

2SK3759

Switching Regulator Applications

Low drain-source ON resistance: RDS (ON) = 0.75 (typ.)

• High forward transfer admittance: $|Y_{fs}| = 6.5S$ (typ.)

• Low leakage current: $IDSS = 100 \mu A (VDS = 500 V)$

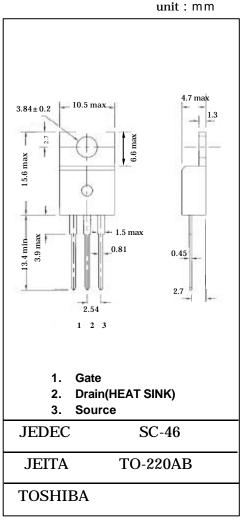
• Enhancement-mode: $V_{th} = 2.0 \sim 4.0 \text{ V}$ ($V_{DS} = 10 \text{ V}$, $I_{D} = 1 \text{ mA}$)

Maximum Ratings (Ta = 25°C)

Characteristics		Symbol	Rating	Unit	
Drain-source voltage		V_{DSS}	500	V	
Drain-gate voltage ($R_{GS} = 20 \text{ k}\Omega$)		V_{DGR}	500	V	
Gate-source voltage		V_{GSS}	±30	V	
	DC (Note 1)	l _D	8		
	Pulse (t = 1 ms) (Note 1)	I _{DP}	32		
Drain power dissipation (Tc = 25°C)		P_{D}	74	W	
Single pulse avalanche energy (Note 2)		E _{AS}	48	_ا	
Avalanche current		l _{AR}	8	Α	
Repetitive avalanche energy (Note 3)		E _{AR}	7.4	mJ	
Channel temperature		T _{ch}	150	°C	
Storage temperature range		T _{stg}	-55~150	°C	

Thermal Characteristics

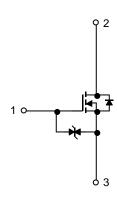
Characteristics	Symbol	Max	Unit
Thermal resistance, channel to case	R _{th (ch-c)}	1.68	°C/W
Thermal resistance, channel to ambient	R _{th (ch-a)}	83.3	°C/W



Weight: 2.0g(typ.)

- Note 1: Please use devices on conditions that the channel temperature is below 150°C.
- Note 2: $V_{DD} = 90 \text{ V}$, $T_{ch} = 25^{\circ}\text{C}$ (initial), L = 1.28 mH, $I_{AR} = 8 \text{ A}$, $R_G = 25 \Omega$
- Note 3: Repetitive rating: Pulse width limited by maximum channel temperature

This transistor is an electrostatic sensitive device. Please handle with caution.





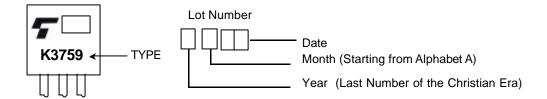
Electrical Characteristics (Ta = 25°C)

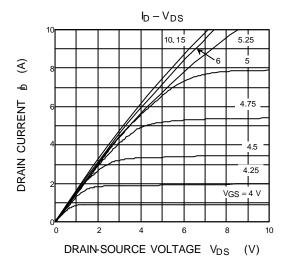
Char	acteristics	Symbol	Test Condition	Min	Тур.	Max	Unit
Gate leakage cu	rrent	l _{GSS}	$V_{GS} = \pm 25 \text{ V}, V_{DS} = 0 \text{ V}$	_	_	±10	μΑ
Gate-source brea	akdown voltage	V (BR) GSS	$I_D = \pm 10 \mu A, V_{GS} = 0 V$	±30		_	V
Drain cut-off curr	ent	I _{DSS}	$V_{DS} = 500 \text{ V}, V_{GS} = 0 \text{ V}$			100	μΑ
Drain-source bre	akdown voltage	V (BR) DSS	$I_D = 10 \text{ mA}, V_{GS} = 0 \text{ V}$	500		_	V
Gate threshold v	oltage	V_{th}	$V_{DS} = 10 \text{ V}, I_D = 1 \text{ mA}$	2.0	_	4.0	V
Drain-source ON	I resistance	R _{DS (ON)}	V _{GS} = 10 V, I _D = 4 A		0.75	0.85	Ω
Forward transfer	admittance	Y _{fs}	$V_{DS} = 10 \text{ V}, I_D = 4 \text{ A}$	3.0	6.5	_	S
Input capacitance		C _{iss}	$V_{DS} = 25 \text{ V}, V_{GS} = 0 \text{ V}, f = 1 \text{ MHz}$	_	1050	_	pF
Reverse transfer capacitance		C _{rss}		_	10	_	
Output capacitance		C _{oss}		_	110	_	
Switching time	Rise time	t _r	$V_{GS} = 4 \text{ A} V_{OUT}$ $V_{GS} = 50 \Omega$ $V_{DD} = 200 \text{ V}$ $V_{DD} = 200 \text{ V}$ $V_{DD} = 10 \mu\text{s}$	_	26	_	
	Turn-on time	t _{on}		_	45	_	
	Fall time	t _f		_	38	_	ns
	Turn-off time	t _{off}		_	130	_	
Total gate charge		Qg		_	28	_	
Gate-source charge		Q_{gs}	$V_{DD} \simeq 400 \text{ V}, V_{GS} = 10 \text{ V}, I_D = 8 \text{ A}$	_	16		nC
Gate-drain charge		Q_{gd}			12		

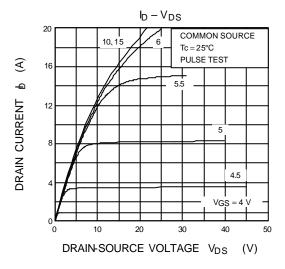
Source-Drain Ratings and Characteristics (Ta = 25°C)

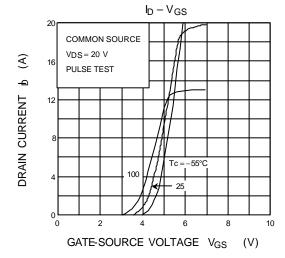
Characteristics	Symbol	Test Condition	Min	Тур.	Max	Unit
Continuous drain reverse current (Note 1)	I _{DR}	_	_		8	Α
Pulse drain reverse current (Note 1)	I _{DRP}	_	_	_	32	Α
Forward voltage (diode)	V_{DSF}	$I_{DR} = 8 \text{ A}, V_{GS} = 0 \text{ V}$	_	_	-1.7	V
Reverse recovery time	t _{rr}	$I_{DR} = 8 A, V_{GS} = 0 V,$	_	1200	_	ns
Reverse recovery charge	Q_{rr}	$dI_{DR}/dt = 100 A/\mu s$	_	10	_	μС

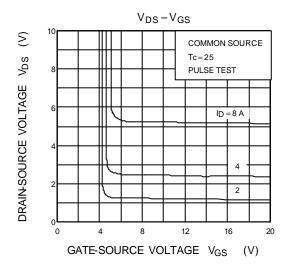
Marking

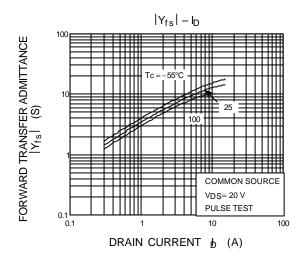


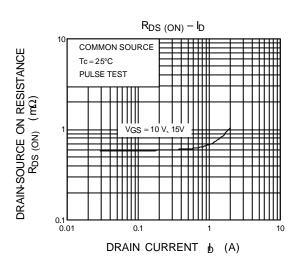


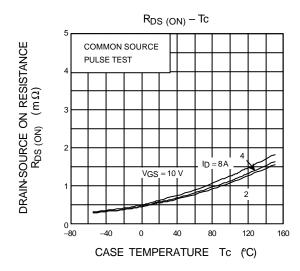


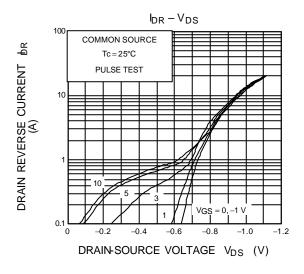


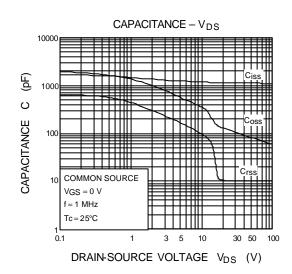


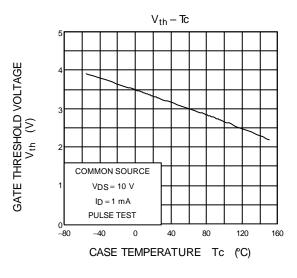


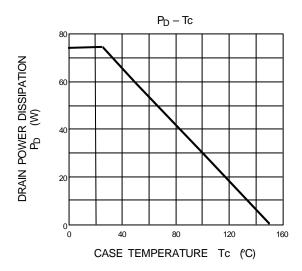


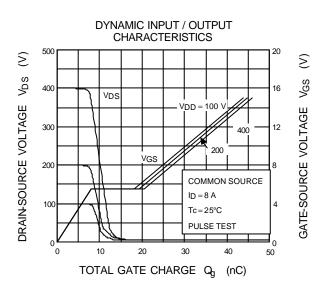


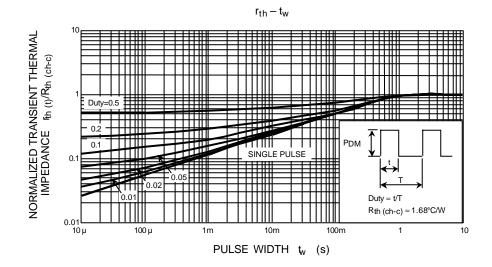


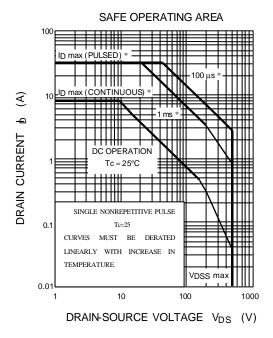


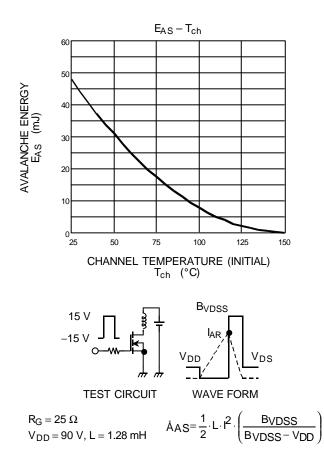












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